

<b>Notice of References Cited</b>	Application/Control No. 10/551,564	Applicant(s)/Patent Under Reexamination AVOLIO ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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	N	wo 2004/065367	01-2004	wo	Beaulieu et al.	-----
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